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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	20MHz
Connectivity	I ² C, LINbus, SPI, UART/USART
Peripherals	LVD, POR, PWM, WDT
Number of I/O	39
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	256 x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/s9s08rn32w1vlf

- Input/Output
 - Up to 55 GPIOs including one output-only pin
 - Two 8-bit keyboard interrupt modules (KBI)
 - Two true open-drain output pins
 - Eight, ultra-high current sink pins supporting 20 mA source/sink current
- Package options
 - 64-pin LQFP
 - 48-pin LQFP
 - 32-pin LQFP

1 Ordering parts

1.1 Determining valid orderable parts

Valid orderable part numbers are provided on the web. To determine the orderable part numbers for this device, go to www.freescale.com and perform a part number search for the following device numbers: RN60, RN48 and RN32.

2 Part identification

2.1 Description

Part numbers for the chip have fields that identify the specific part. You can use the values of these fields to determine the specific part you have received.

2.2 Format

Part numbers for this device have the following format:

S 9 S08 RN AA F1 B CC

2.3 Fields

This table lists the possible values for each field in the part number (not all combinations are valid):

Field	Description	Values
S	Qualification status	<ul style="list-style-type: none"> S = fully qualified, general market flow
9	Memory	<ul style="list-style-type: none"> 9 = flash based
S08	Core	<ul style="list-style-type: none"> S08 = 8-bit CPU
RN	Device family	<ul style="list-style-type: none"> RN
AA	Approximate flash size in KB	<ul style="list-style-type: none"> 60 = 60 KB 48 = 48 KB 32 = 32 KB
F1	Fab and mask set identifier	<ul style="list-style-type: none"> W1
B	Temperature range (°C)	<ul style="list-style-type: none"> M = -40 to 125

Table continues on the next page...

2. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

4.2 Moisture handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
MSL	Moisture sensitivity level	—	3	—	1

1. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

4.3 ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
V_{HBM}	Electrostatic discharge voltage, human body model	-6000	+6000	V	1
V_{CDM}	Electrostatic discharge voltage, charged-device model	-500	+500	V	2
I_{LAT}	Latch-up current at ambient temperature of 125°C	-100	+100	mA	

1. Determined according to JEDEC Standard JESD22-A114, *Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)*.
 2. Determined according to JEDEC Standard JESD22-C101, *Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components*.

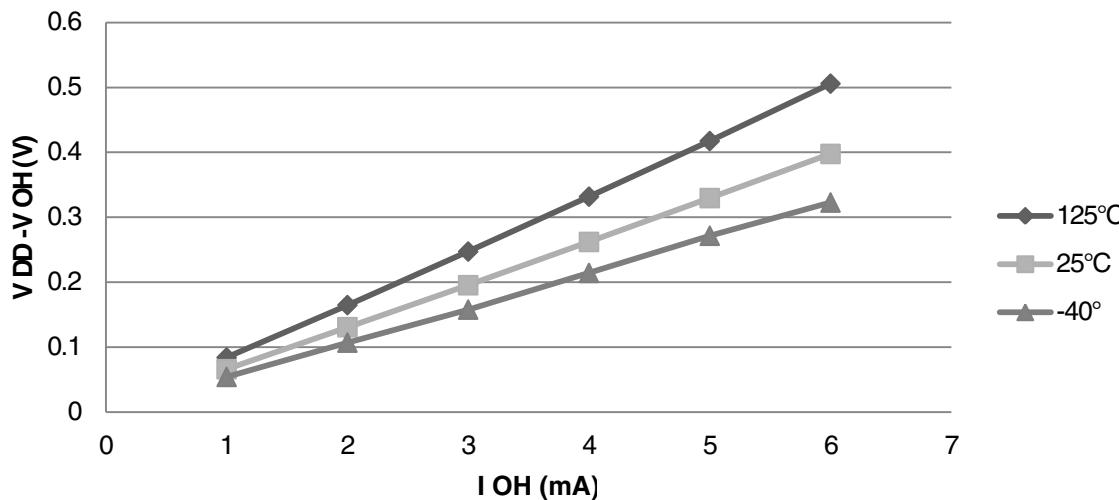
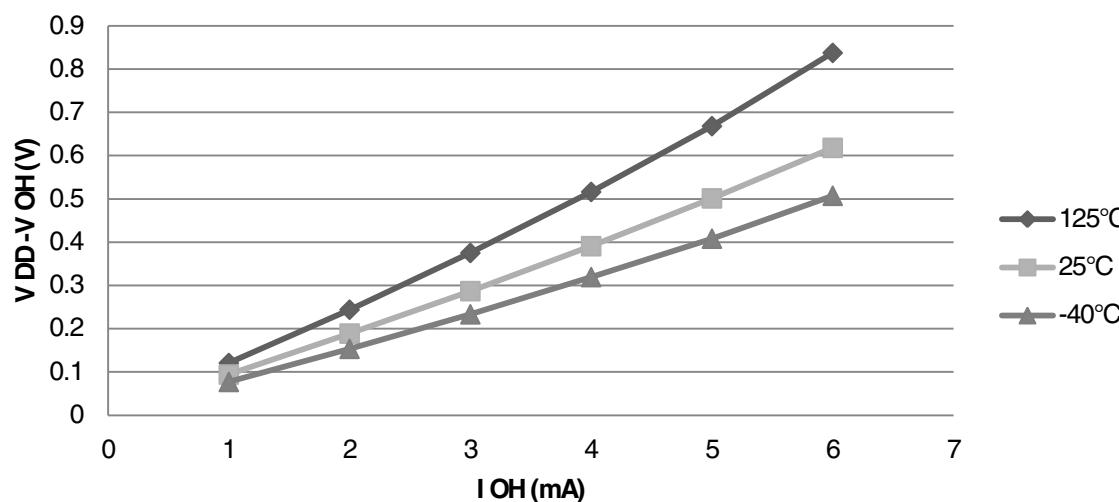
4.4 Voltage and current operating ratings

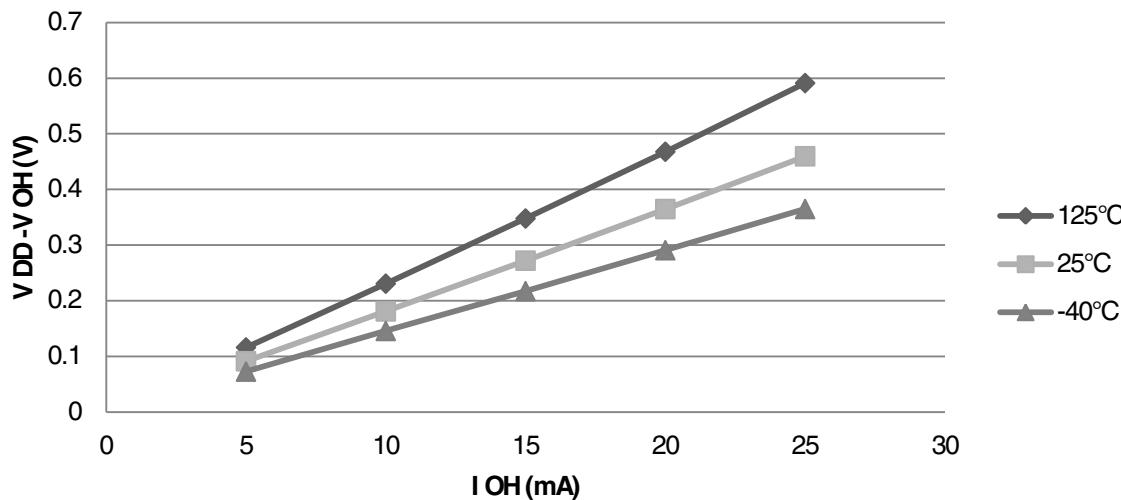
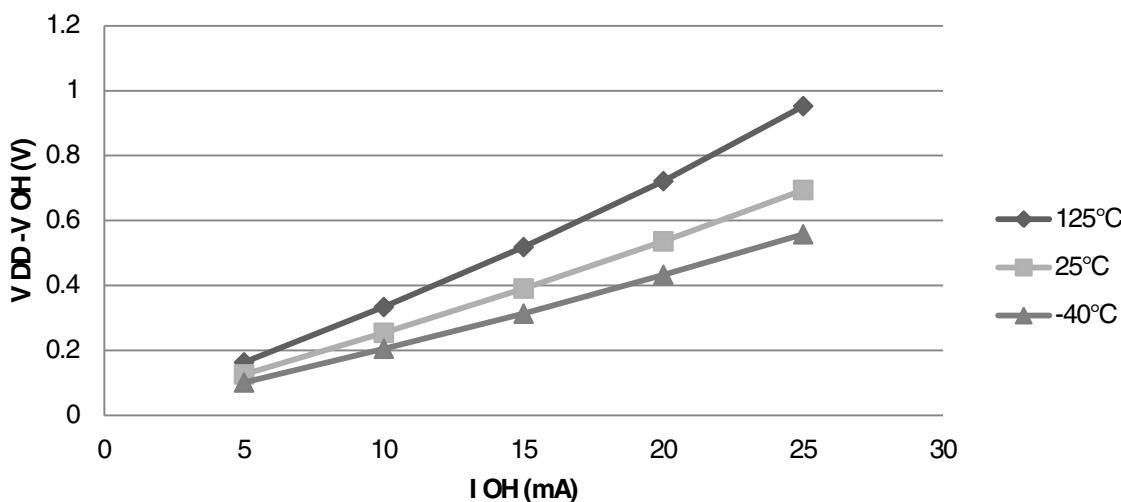
Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Stress beyond the limits specified in below table may affect device reliability or cause permanent damage to the device. For functional operating conditions, refer to the remaining tables in this document.

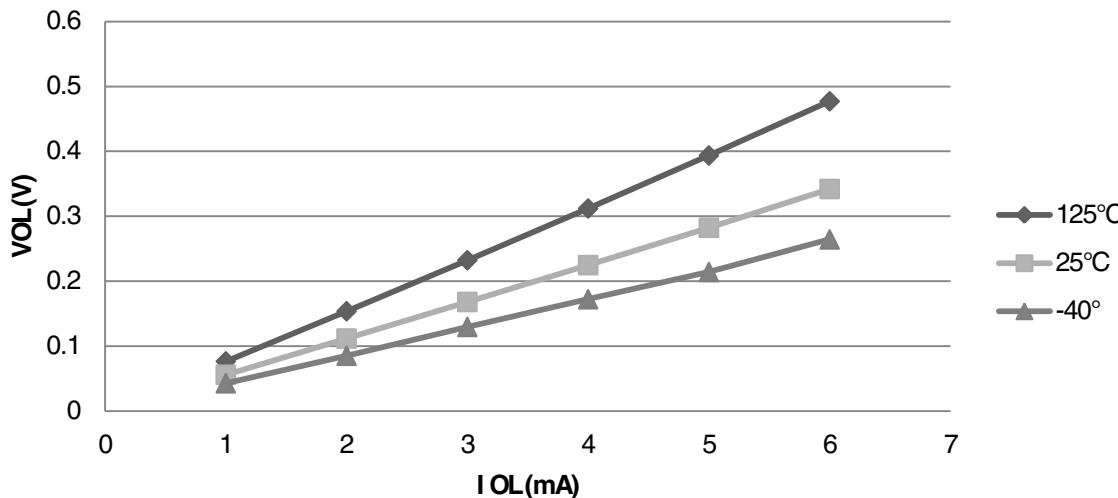
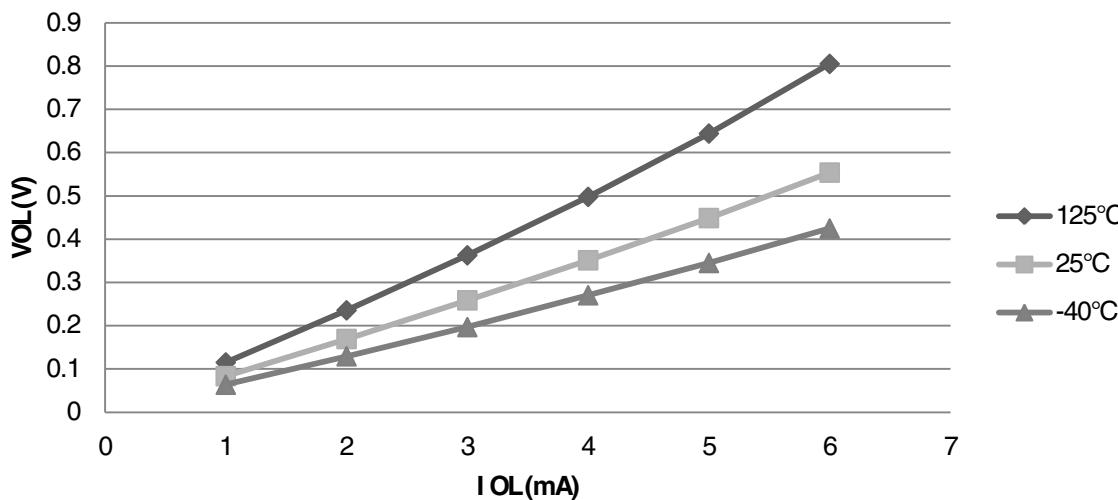
This device contains circuitry protecting against damage due to high static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (for instance, either V_{SS} or V_{DD}) or the programmable pullup resistor associated with the pin is enabled.

Symbol	Description	Min.	Max.	Unit
V_{DD}	Supply voltage	-0.3	5.8	V
I_{DD}	Maximum current into V_{DD}	—	120	mA

Table continues on the next page...

Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (low drive strength) ($V_{DD} = 5\text{ V}$)**Figure 1. Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (standard drive strength) ($V_{DD} = 5\text{ V}$)****Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (low drive strength) ($V_{DD} = 3\text{ V}$)****Figure 2. Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (standard drive strength) ($V_{DD} = 3\text{ V}$)**

Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (high drive strength) ($V_{DD} = 5\text{ V}$)**Figure 3. Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (high drive strength) ($V_{DD} = 5\text{ V}$)****Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (high drive strength) ($V_{DD} = 3\text{ V}$)****Figure 4. Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (high drive strength) ($V_{DD} = 3\text{ V}$)**

Typical I_{OL} Vs. V_{OL}(low drive strength) (V_{DD} = 5 V)**Figure 5. Typical I_{OL} Vs. V_{OL} (standard drive strength) (V_{DD} = 5 V)****Typical I_{OL} Vs. V_{OL}(low drive strength) (V_{DD} = 3 V)****Figure 6. Typical I_{OL} Vs. V_{OL} (standard drive strength) (V_{DD} = 3 V)**

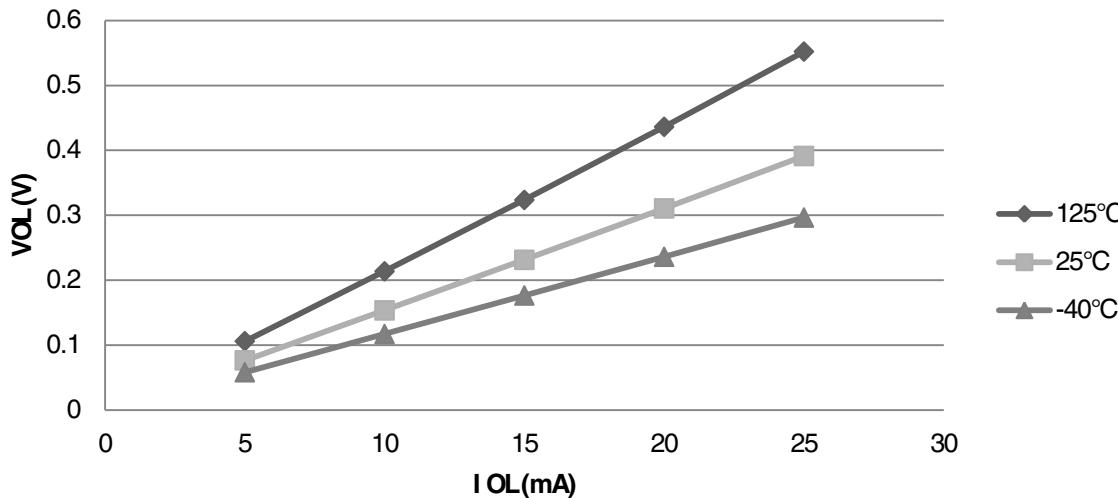
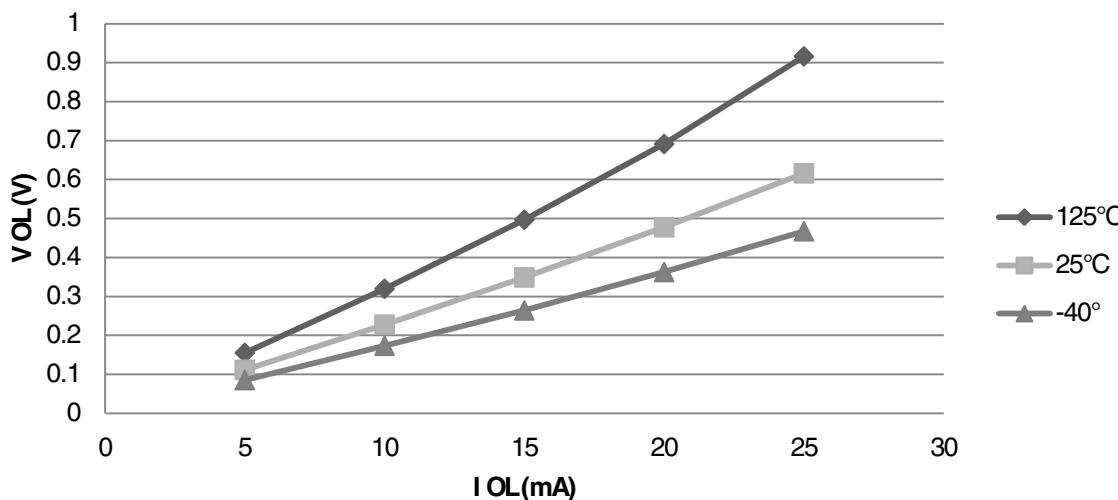
Typical I_{OL} Vs. V_{OL} (high drive strength) ($V_{DD} = 5\text{ V}$)**Figure 7. Typical I_{OL} Vs. V_{OL} (high drive strength) ($V_{DD} = 5\text{ V}$)****Typical I_{OL} Vs. V_{OL} (high drive strength) ($V_{DD} = 3\text{ V}$)****Figure 8. Typical I_{OL} Vs. V_{OL} (high drive strength) ($V_{DD} = 3\text{ V}$)**

Table 4. Supply current characteristics (continued)

Num	C	Parameter	Symbol	Bus Freq	V _{DD} (V)	Typical ¹	Max	Unit	Temp
7	C	ADC adder to stop3 ADLPC = 1 ADLSMP = 1 ADCO = 1 MODE = 10B ADICLK = 11B	—	—	5	44	—	μA	-40 to 125 °C
	C				3	40	—		
8	C	TSI adder to stop3 ⁴ PS = 010B NSCN = 0x0F EXTCHRG = 0 REFCHRG = 0 DVOLT = 01B	—	—	5	111	—	μA	-40 to 125 °C
	C				3	110	—		
9	C	LVD adder to stop3 ⁵	—	—	5	130	—	μA	-40 to 125 °C
	C				3	125	—		

1. Data in Typical column was characterized at 5.0 V, 25 °C or is typical recommended value.
2. RTC adder cause <1 μA I_{DD} increase typically, RTC clock source is 1 kHz LPO clock.
3. ACMP adder cause <1 μA I_{DD} increase typically.
4. The current varies with TSI configuration and capacity of touch electrode. Please refer to [TSI electrical specifications](#).
5. LVD is periodically woken up from stop3 by 5% duty cycle. The period is equal to or less than 2 ms.

5.1.3 EMC performance

Electromagnetic compatibility (EMC) performance is highly dependant on the environment in which the MCU resides. Board design and layout, circuit topology choices, location and characteristics of external components as well as MCU software operation all play a significant role in EMC performance. The system designer should consult Freescale applications notes such as AN2321, AN1050, AN1263, AN2764, and AN1259 for advice and guidance specifically targeted at optimizing EMC performance.

5.1.3.1 EMC radiated emissions operating behaviors

5.2.2 Debug trace timing specifications

Table 6. Debug trace operating behaviors

Symbol	Description	Min.	Max.	Unit
t_{cyc}	Clock period		Frequency dependent	MHz
t_{wl}	Low pulse width	2	—	ns
t_{wh}	High pulse width	2	—	ns
t_r	Clock and data rise time	—	3	ns
t_f	Clock and data fall time	—	3	ns
t_s	Data setup	3	—	ns
t_h	Data hold	2	—	ns

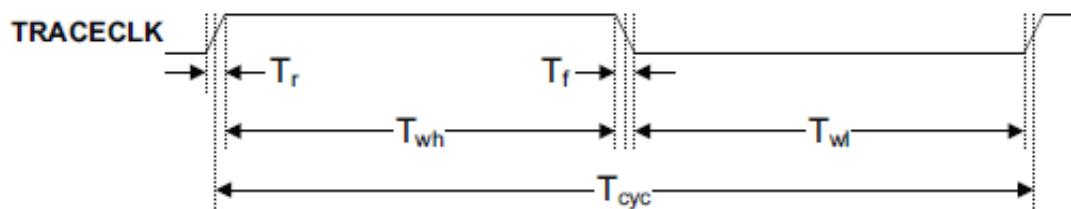


Figure 11. TRACE_CLKOUT specifications

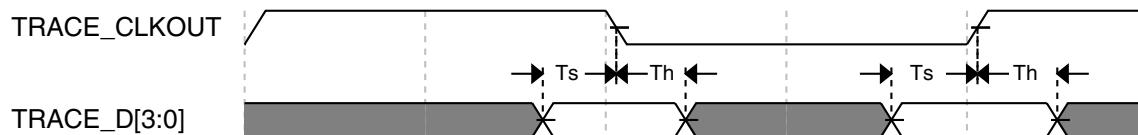


Figure 12. Trace data specifications

5.2.3 FTM module timing

Synchronizer circuits determine the shortest input pulses that can be recognized or the fastest clock that can be used as the optional external source to the timer counter. These synchronizers operate from the current bus rate clock.

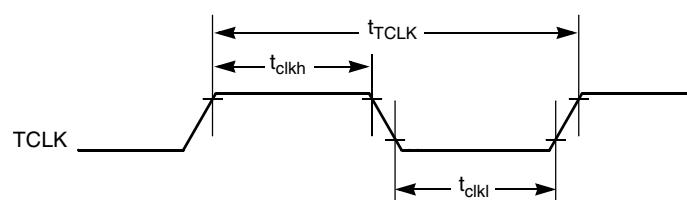
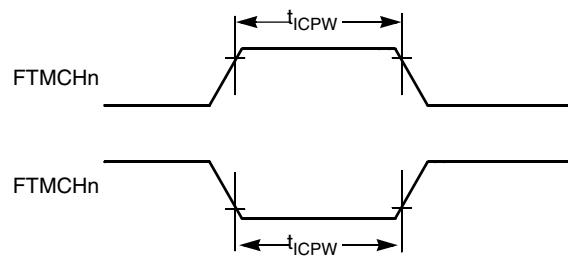
Table 7. FTM input timing

No.	C	Function	Symbol	Min	Max	Unit
1	D	External clock frequency	f_{TCLK}	0	$f_{Bus}/4$	Hz

Table continues on the next page...

Table 7. FTM input timing (continued)

No.	C	Function	Symbol	Min	Max	Unit
2	D	External clock period	t_{TCLK}	4	—	t_{cyc}
3	D	External clock high time	t_{clkh}	1.5	—	t_{cyc}
4	D	External clock low time	t_{clkL}	1.5	—	t_{cyc}
5	D	Input capture pulse width	t_{ICPW}	1.5	—	t_{cyc}

**Figure 13. Timer external clock****Figure 14. Timer input capture pulse**

5.3 Thermal specifications

5.3.1 Thermal characteristics

This section provides information about operating temperature range, power dissipation, and package thermal resistance. Power dissipation on I/O pins is usually small compared to the power dissipation in on-chip logic and voltage regulator circuits, and it is user-determined rather than being controlled by the MCU design. To take $P_{I/O}$ into account in power calculations, determine the difference between actual pin voltage and V_{SS} or V_{DD} and multiply by the pin current for each I/O pin. Except in cases of unusually high pin current (heavy loads), the difference between pin voltage and V_{SS} or V_{DD} will be very small.

Table 8. Thermal characteristics

Rating	Symbol	Value	Unit
Operating temperature range (packaged)	T _A	T _L to T _H -40 to 125	°C
Junction temperature range	T _J	-40 to 135	°C
Thermal resistance single-layer board			
64-pin LQFP	θ _{JA}	71	°C/W
48-pin LQFP	θ _{JA}	81	°C/W
32-pin LQFP	θ _{JA}	86	°C/W
Thermal resistance four-layer board			
64-pin LQFP	θ _{JA}	53	°C/W
48-pin LQFP	θ _{JA}	57	°C/W
32-pin LQFP	θ _{JA}	57	°C/W

The average chip-junction temperature (T_J) in °C can be obtained from:

$$T_J = T_A + (P_D \times \theta_{JA})$$

Where:

T_A = Ambient temperature, °C

θ_{JA} = Package thermal resistance, junction-to-ambient, °C/W

$$P_D = P_{int} + P_{I/O}$$

P_{int} = I_{DD} × V_{DD}, Watts - chip internal power

P_{I/O} = Power dissipation on input and output pins - user determined

For most applications, P_{I/O} << P_{int} and can be neglected. An approximate relationship between P_D and T_J (if P_{I/O} is neglected) is:

$$P_D = K \div (T_J + 273 \text{ °C})$$

Solving the equations above for K gives:

$$K = P_D \times (T_A + 273 \text{ °C}) + \theta_{JA} \times (P_D)^2$$

where K is a constant pertaining to the particular part. K can be determined by measuring P_D (at equilibrium) for a known T_A. Using this value of K, the values of P_D and T_J can be obtained by solving the above equations iteratively for any value of T_A.

6 Peripheral operating requirements and behaviors

Program and erase operations do not require any special power sources other than the normal V_{DD} supply. For more detailed information about program/erase operations, see the Memory section.

6.3 Analog

6.3.1 ADC characteristics

Table 11. 5 V 12-bit ADC operating conditions

Characteristic	Conditions	Symb	Min	Typ ¹	Max	Unit	Comment
Supply voltage	Absolute	V _{DDA}	2.7	—	5.5	V	—
	Delta to V _{DD} (V _{DD} -V _{DDAD})	ΔV _{DDA}	-100	0	+100	mV	—
Ground voltage	Delta to V _{SS} (V _{SS} -V _{SSA}) ²	ΔV _{SSA}	-100	0	+100	mV	—
Input voltage		V _{ADIN}	V _{REFL}	—	V _{REFH}	V	—
Input capacitance		C _{ADIN}	—	4.5	5.5	pF	—
Input resistance		R _{ADIN}	—	3	5	kΩ	—
Analog source resistance	12-bit mode • f _{ADCK} > 4 MHz • f _{ADCK} < 4 MHz	R _{AS}	—	—	2	kΩ	External to MCU
	—		—	—	5		
	10-bit mode • f _{ADCK} > 4 MHz • f _{ADCK} < 4 MHz		—	—	5		
	—		—	—	10		
	8-bit mode (all valid f _{ADCK})		—	—	10		
ADC conversion clock frequency	High speed (ADLPC=0)	f _{ADCK}	0.4	—	8.0	MHz	—
	Low power (ADLPC=1)		0.4	—	4.0		

1. Typical values assume V_{DDA} = 5.0 V, Temp = 25°C, f_{ADCK}=1.0 MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
2. DC potential difference.

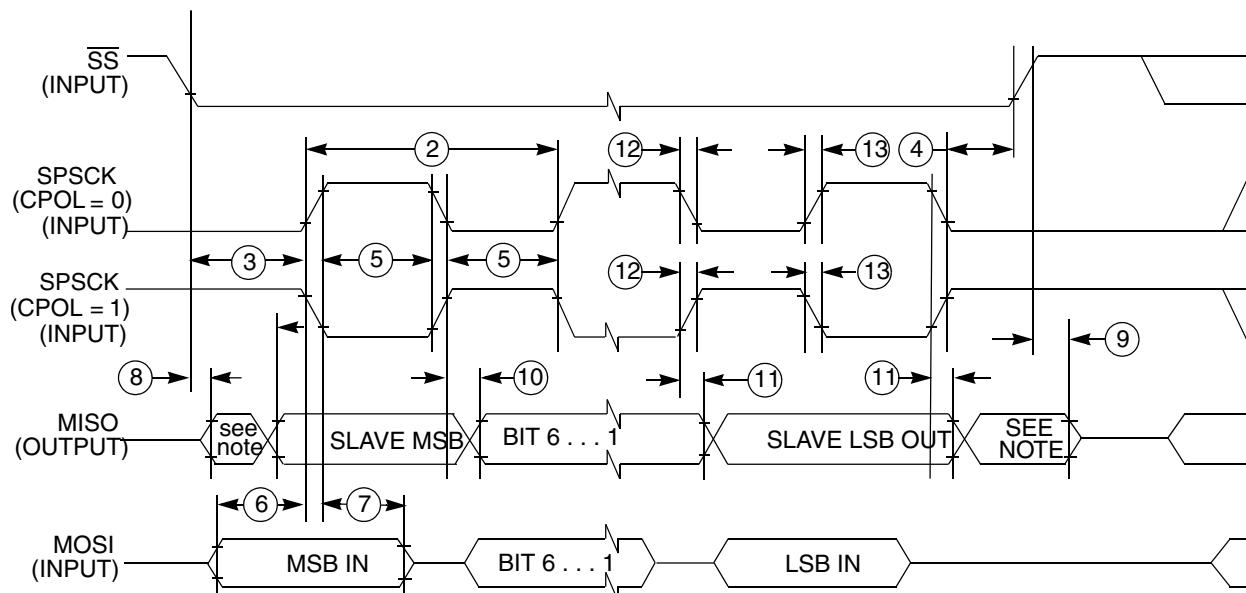
Table 12. 12-bit ADC Characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$) (continued)

Characteristic	Conditions	C	Symb	Min	Typ ¹	Max	Unit
ADC asynchronous clock source	High speed (ADLPC = 0)	P	f _{ADACK}	2	3.3	5	MHz
	Low power (ADLPC = 1)			1.25	2	3.3	
Conversion time (including sample time)	Short sample (ADLSMP = 0)	T	t _{ADC}	—	20	—	ADCK cycles
	Long sample (ADLSMP = 1)			—	40	—	
Sample time	Short sample (ADLSMP = 0)	T	t _{ADS}	—	3.5	—	ADCK cycles
	Long sample (ADLSMP = 1)			—	23.5	—	
Total unadjusted Error ^{2, 2}	12-bit mode	T	E _{TUE}	—	±5.0	—	LSB ^{3, 3}
	10-bit mode	P		—	±1.5	±2.0	
	8-bit mode	P		—	±0.7	±1.0	
Differential Non-Linearity	12-bit mode	T	DNL	—	±1.0	—	LSB ³
	10-bit mode ^{4, 4}	P		—	±0.25	±0.5	
	8-bit mode ⁴	P		—	±0.15	±0.25	
Integral Non-Linearity	12-bit mode	T	INL	—	±1.0	—	LSB ³
	10-bit mode	T		—	±0.3	±0.5	
	8-bit mode	T		—	±0.15	±0.25	
Zero-scale error ^{5, 5}	12-bit mode	C	E _{ZS}	—	±2.0	—	LSB ³
	10-bit mode	P		—	±0.25	±1.0	
	8-bit mode	P		—	±0.65	±1.0	
Full-scale error ⁶	12-bit mode	T	E _{FS}	—	±2.5	—	LSB ³
	10-bit mode	T		—	±0.5	±1.0	
	8-bit mode	T		—	±0.5	±1.0	
Quantization error	≤12 bit modes	D	E _Q	—	—	±0.5	LSB ³
Input leakage error ⁷	all modes	D	E _{IL}	I _{in} * R _{AS}			mV
Temp sensor slope	-40°C– 25°C	D	m	—	3.266	—	mV/°C
	25°C– 125°C			—	3.638	—	
Temp sensor voltage	25°C	D	V _{TEMP25}	—	1.396	—	V

1. Typical values assume $V_{DDA} = 5.0$ V, Temp = 25°C, f_{ADCK}=1.0 MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
2. Includes quantization.
3. 1 LSB = $(V_{REFH} - V_{REFL})/2^N$
4. Monotonicity and no-missing-codes guaranteed in 10-bit and 8-bit modes
5. $V_{ADIN} = V_{SSA}$
6. $V_{ADIN} = V_{DDA}$
7. I_{in} = leakage current (refer to DC characteristics)

Table 15. SPI slave mode timing

Nu. m.	Symbol	Description	Min.	Max.	Unit	Comment
1	f_{op}	Frequency of operation	0	$f_{Bus}/4$	Hz	f_{Bus} is the bus clock as defined in .
2	t_{SPSCK}	SPSCK period	$4 \times t_{Bus}$	—	ns	$t_{Bus} = 1/f_{Bus}$
3	t_{Lead}	Enable lead time	1	—	t_{Bus}	—
4	t_{Lag}	Enable lag time	1	—	t_{Bus}	—
5	t_{WSPSCK}	Clock (SPSCK) high or low time	$t_{Bus} - 30$	—	ns	—
6	t_{SU}	Data setup time (inputs)	15	—	ns	—
7	t_{HI}	Data hold time (inputs)	25	—	ns	—
8	t_a	Slave access time	—	t_{Bus}	ns	Time to data active from high-impedance state
9	t_{dis}	Slave MISO disable time	—	t_{Bus}	ns	Hold time to high-impedance state
10	t_v	Data valid (after SPSCK edge)	—	25	ns	—
11	t_{HO}	Data hold time (outputs)	0	—	ns	—
12	t_{RI}	Rise time input	—	$t_{Bus} - 25$	ns	—
	t_{FI}	Fall time input	—	—	—	—
13	t_{RO}	Rise time output	—	25	ns	—
	t_{FO}	Fall time output	—	—	—	—



NOTE: Not defined

Figure 19. SPI slave mode timing (CPHA = 0)

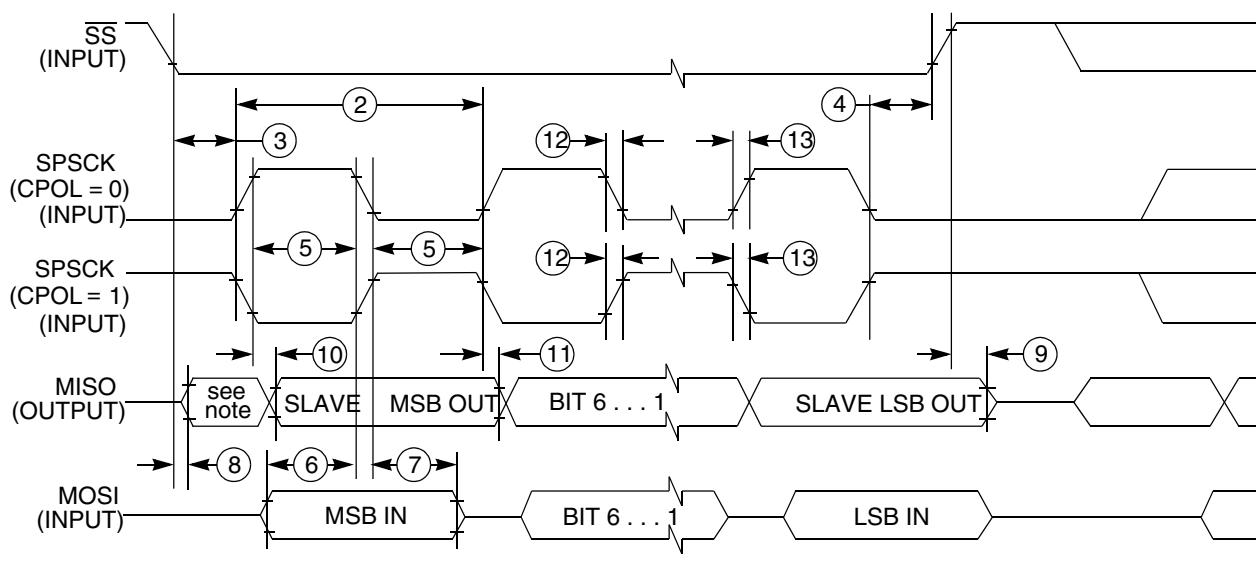


Figure 20. SPI slave mode timing (CPHA=1)

6.5 Human-machine interfaces (HMI)

6.5.1 TSI electrical specifications

Table 16. TSI electrical specifications

Symbol	Description	Min.	Type	Max	Unit
TSI_RUNF	Fixed power consumption in run mode	—	100	—	µA
TSI_RUNV	Variable power consumption in run mode (depends on oscillator's current selection)	1.0	—	128	µA
TSI_EN	Power consumption in enable mode	—	100	—	µA
TSI_DIS	Power consumption in disable mode	—	1.2	—	µA
TSI_TEN	TSI analog enable time	—	66	—	µs
TSI_CREF	TSI reference capacitor	—	1.0	—	pF
TSI_DVOLT	Voltage variation of VP & VM around nominal values	-10	—	10	%

7 Dimensions

7.1 Obtaining package dimensions

Package dimensions are provided in package drawings.

To find a package drawing, go to freescale.com and perform a keyword search for the drawing's document number:

If you want the drawing for this package	Then use this document number
32-pin LQFP	98ASH70029A
48-pin LQFP	98ASH00962A
64-pin LQFP	98ASS23234W

8 Pinout

8.1 Signal multiplexing and pin assignments

The following table shows the signals available on each pin and the locations of these pins on the devices supported by this document. The Port Control Module is responsible for selecting which ALT functionality is available on each pin.

Table 17. Pin availability by package pin-count

Pin Number			Lowest Priority <--> Highest				
64-LQFP	48-LQFP	32-LQFP	Port Pin	Alt 1	Alt 2	Alt 3	Alt 4
1	1	1	PTD1 ^{1, 1}	KBI1P1	FTM2CH3	MOSI1	—
2	2	2	PTD0 ¹	KBI1P0	FTM2CH2	SPSCK1	—
3	—	—	PTH7	—	—	—	—
4	—	—	PTH6	—	—	—	—
5	3	—	PTE7	—	TCLK2	—	—
6	4	—	PTH2	—	BUSOUT	—	—
7	5	3	—	—	—	—	V _{DD}
8	6	4	—	—	—	V _{DDA}	V _{REFH}
9	7	5	—	—	—	V _{SSA}	V _{REFL}
10	8	6	—	—	—	—	V _{SS}
11	9	7	PTB7	—	SCL	—	EXTAL
12	10	8	PTB6	—	SDA	—	XTAL
13	11	—	—	—	—	—	V _{SS}
14	—	—	PTH1 ¹	—	FTM2CH1	—	—
15	—	—	PTH0 ¹	—	FTM2CH0	—	—
16	12	—	PTE6	—	—	—	—
17	13	—	PTE5	—	—	—	—
18	14	9	PTB5 ¹	FTM2CH5	SS0	—	—
19	15	10	PTB4 ¹	FTM2CH4	MISO0	—	—

Table continues on the next page...

Table 17. Pin availability by package pin-count (continued)

Pin Number			Lowest Priority <--> Highest				
64-LQFP	48-LQFP	32-LQFP	Port Pin	Alt 1	Alt 2	Alt 3	Alt 4
20	16	11	PTC3	FTM2CH3	—	ADP11	—
21	17	12	PTC2	FTM2CH2	—	ADP10	—
22	18	—	PTD7	KBI1P7	TXD2	—	—
23	19	—	PTD6	KBI1P6	RXD2	—	—
24	20	—	PTD5	KBI1P5	—	—	—
25	21	13	PTC1	—	FTM2CH1	ADP9	TSI7
26	22	14	PTC0	—	FTM2CH0	ADP8	TSI6
27	—	—	PTF7	—	—	ADP15	—
28	—	—	PTF6	—	—	ADP14	—
29	—	—	PTF5	—	—	ADP13	—
30	—	—	PTF4	—	—	ADP12	—
31	23	15	PTB3	KBI0P7	MOSI0	ADP7	TSI5
32	24	16	PTB2	KBI0P6	SPSCK0	ADP6	TSI4
33	25	17	PTB1	KBI0P5	TXD0	ADP5	TSI3
34	26	18	PTB0	KBI0P4	RXD0	ADP4	TSI2
35	—	—	PTF3	—	—	—	TSI15
36	—	—	PTF2	—	—	—	TSI14
37	27	19	PTA7	FTM2FAULT2	—	ADP3	TSI1
38	28	20	PTA6	FTM2FAULT1	—	ADP2	TSI0
39	29	—	PTE4	—	—	—	—
40	30	—	—	—	—	—	V _{SS}
41	31	—	—	—	—	—	V _{DD}
42	—	—	PTF1	—	—	—	TSI13
43	—	—	PTF0	—	—	—	TSI12
44	32	—	PTD4	KBI1P4	—	—	—
45	33	21	PTD3	KBI1P3	SS1	—	TSI11
46	34	22	PTD2	KBI1P2	MISO1	—	TSI10
47	35	23	PTA3 ^{2, 2}	KBI0P3	TXD0	SCL	—
48	36	24	PTA2 ²	KBI0P2	RXD0	SDA	—
49	37	25	PTA1	KBI0P1	FTM0CH1	ACMP1	ADP1
50	38	26	PTA0	KBI0P0	FTM0CH0	ACMP0	ADP0
51	39	27	PTC7	—	TxD1	—	TSI9
52	40	28	PTC6	—	RxD1	—	TSI8
53	41	—	PTE3	—	SS0	—	—
54	42	—	PTE2	—	MISO0	—	—
55	—	—	PTG3	—	—	—	—
56	—	—	PTG2	—	—	—	—
57	—	—	PTG1	—	—	—	—

Table continues on the next page...

8.2 Device pin assignment

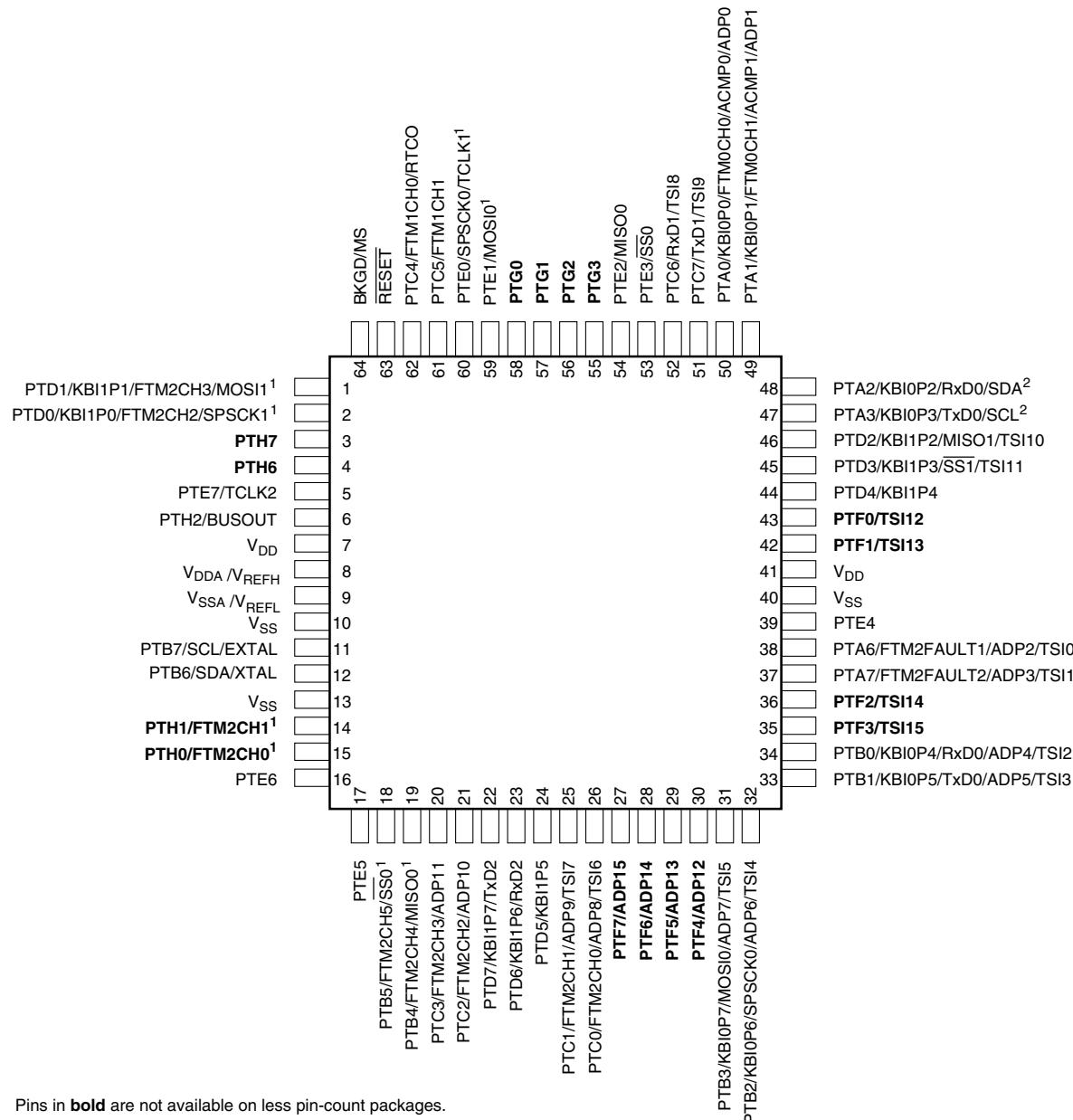


Figure 21. S9S08RN60 64-pin LQFP package

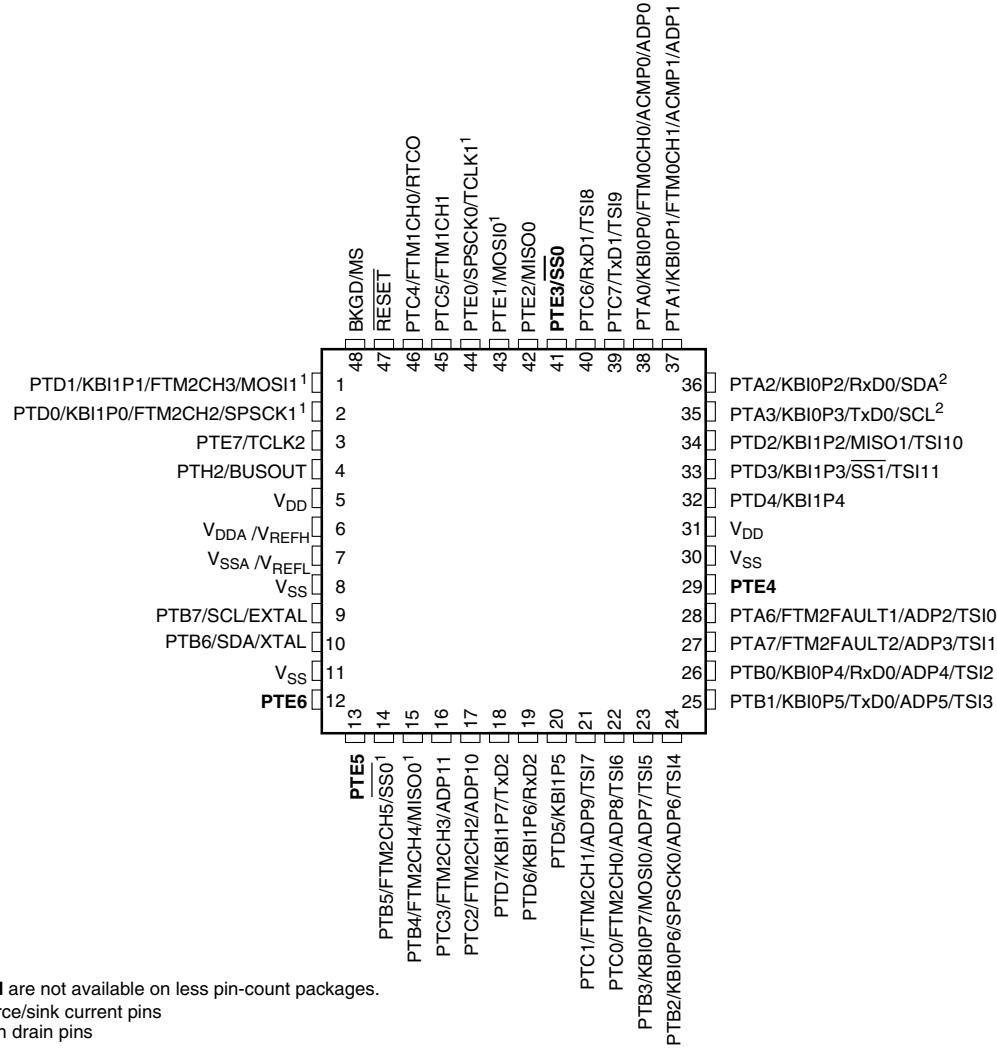
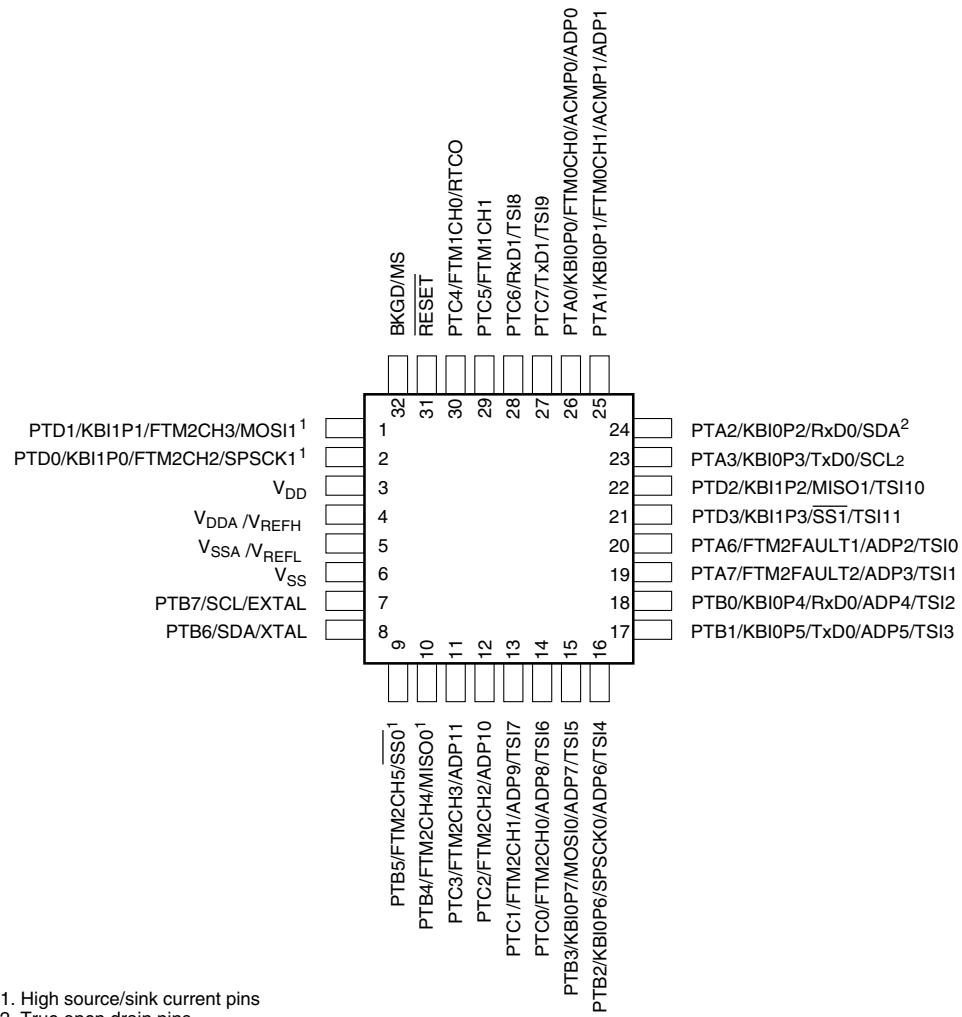


Figure 22. S9S08RN60 48-pin LQFP package

**Figure 23. S9S08RN60 32-pin LQFP package**

9 Revision history

The following table provides a revision history for this document.

Table 18. Revision history

Rev. No.	Date	Substantial Changes
1	01/2014	Initial Release